

**ANNEXURE IV (A) - PRE-QUALIFICATION CRITERIA**

The evidence of Photonics Chip Fabrication Foundry Facility in India along with following details must be submitted:

- a) Infrastructure and Technical Capabilities
- b) Address of 3 users during last two years

**ANNEXURE IV (B) – TECHNICAL SPECIFICATIONS**

<b>TECHNICAL SPECIFICATION OF SILICON PHOTONIC CHIP TAPE OUT IN SILICON ON INSULATOR PLATFORM</b>		
<b>A. SILICON ON INSULATOR SPECIFICATIONS</b>		
1	Silicon Substrate Thickness	~ 700 $\mu\text{m}$
2	Buried Oxide (BOX) Thickness	~ 2 $\mu\text{m}$
3	Silicon Device Layer Thickness	220 nm
4	Top Cladding Material	Silicon Dioxide
5	Top Cladding Thickness	~ 3 $\mu\text{m}$
6	Doping Type of Silicon Device Layer	P type
7	Doping Concentration of Silicon Device Layer	$1\text{e}15 \text{ cm}^{-3}$
<b>B. DESIGN FLEXIBILITY</b>		
1	Waveguide Etch Depths	220 nm, 130 nm, 70 nm
2	Min Waveguide Width	130 nm
3	Min Separation Between Two Waveguides	200 nm
4	Waveguide Width Variation	$\pm 25 \text{ nm}$
5	Etch Depth Variation	$\pm 10 \text{ nm}$
6	Waveguide Loss	< 3 dB/cm
7	Tapering Between Different etched Waveguides	Must Have
<b>C. DEVICE LIBRARY REQUIREMENTS: PASSIVE</b>		
1	Grating Coupler	
	a. Inclined Angle with Vertical	10 degree
	b. Peak Wavelength	1550 nm
	c. Coupling Loss	< 6 dB/facet
	d. 1 dB Bandwidth	20 nm
2	Edge Coupler: Coupling Loss	< 3 dB/facet
3	Power Splitter( 2 $\times$ 2 and 1 $\times$ 2)	
	a. Splitting Efficiency at 1550 nm	3 dB
	b. Insertion Loss	< 0.2 dB
4	Waveguide Crossing	
	a. Insertion Loss	< 0.2 dB
	b. Crosstalk	< - 40 dB
5	Polarization Beam Splitter ( 1 $\times$ 2)	
	a. Insertion Loss	< 0.3 dB

<b>D.</b>	<b>BACK END SPECIFICATIONS</b>	
1	Number of Metal Layers	$\geq 2$
2	Sheet Resistance of Metal Layers	25-45 milli ohm/square
3	Metal Heater for Waveguide Tuning	
	a. Material	TiN
	b. Sheet Resistance	10-14 ohm/square
	c. Distance From Top of The Waveguide	$\sim 2 \mu\text{m}$
	d. Minimum Width	$2 \mu\text{m}$
4	Top Cladding Bond Pad Opening	$> 50 \times 50 \mu\text{m}^2$
5	Options for Top Cladding Oxide Opening upto BOX	YES
6	Deep Trench For Edge Coupling	YES
<b>E.</b>	<b>DEVICE LIBRARY REQUIREMENTS: ACTIVE</b>	
1	Required Doping concentration (Both p and n type)	$1e18 \text{ cm}^{-3}, 2.5e19 \text{ cm}^{-3}$
2.	Modulator	
	a. Insertion Loss	$< 4 \text{ dB}$
	b. $V\pi$	$< 10 \text{ Volt}$
	c. $V\pi L$	$< 2.5 \text{ Volt-cm}$
	d. Bandwidth	$> 35 \text{ GHz}$
3	Photo Detector	
	a. Responsivity	$> 0.85 \text{ Amp/Watt}$
	b. Bandwidth	$> 35 \text{ GHz}$
	c. Dark Current	$< 50 \text{ nano Amp}$
<b>F.</b>	<b>REQUIRED DOCUMENTATIONS</b>	
1	Device Library Book	Photonic Design Kit should be compatible with Ansys Lumerical
2	Layout and Technology Handbook	GDS II sample LayOut file should be provided
3	Design Rule Check Script	Should be compatible with KLayout
<b>G</b>	<b>CHIP DIMENSION: <math>3 \times 16 \text{ mm}^2</math></b>	
<b>H</b>	<b>NUMBER OF DIES: At least 15</b>	
<b>I.</b>	<b>DELIVERY TIME:</b>	
<b>J.</b>	Parent company should be an established company with good number of silicon photonic Multi Project Wafer runs (at least 50, Wafer size – 200/300 mm)	
<b>K</b>		
<b>L.</b>	<b>OPTIONAL</b>	
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**NOTE: The bidder has to provide a Technical compliance statement - Mentioning (Complied / Not complied)**

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